

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Connectors for electrical and electronic equipment –
Tests and measurements –
Part 28-100: Signal integrity tests up to 2 000 MHz – Tests 28a to 28g**

**Connecteurs pour équipements électriques et électroniques –
Essais et mesures –
Partie 28-100: Essais d'intégrité des signaux jusqu'à 2 000 MHz – Essais
28a à 28g**





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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**CONNECTORS FOR ELECTRICAL AND ELECTRONIC EQUIPMENT –
TESTS AND MEASUREMENTS –****Part 28-100: Signal integrity tests up to 2 000 MHz –
Tests 28a to 28g**

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International Standard IEC 60512-28-100 has been prepared by subcommittee 48B: Electrical connectors, of IEC technical committee 48: Electrical connectors and mechanical structures for electrical and electronic equipment.

This second edition cancels and replaces the first edition, issued in 2013, and constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- The title is revised from 1 000 MHz to 2 000 MHz to reflect the range of frequencies which may be tested.
- All tables and requirements have been revised up to 2 000 MHz.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
48B/2756/FDIS	48B/2766/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

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